

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/069,118	HATANAKA ET AL.
Examiner	Art Unit	
Shin-Hon Chen	2131	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
380	201,217	8/23/2006	S.C.
380	235-250	8/23/2006	S.C.
380	281	8/23/2006	S.C.
713/165-168; 705/57		8/23/2006	S.C.